

RESEARCH OF OPTICAL PROPERTIES
OF SURFACE LAYERS OF OPTICAL GLASSES
K-8 AND TF-5 BY THE ELLIPSOMETRICAL
METHOD AFTER ELECTRON BEAM
PROCESSING

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S u m m a r y

The problems of the modern technology of electron beam processing of substrates from an optical glass are discussed. The ellipsometrical method is applied to research the influence of electron beam processing. Using a mathematical processor MATHCAD allows carrying out the necessary calculations to interpret ellipsometrical measurements. The information about optical properties of the surface layers of substrates, from optical glasses K-8 and TF-5 after electron beam processing was received on the basis of ellipsometrical researches. In thin surfaces layers of these substrates, insignificant physico-chemical transformations take place, which are reflected in their operational properties.